

# Search Notes



Application/Control No.

10/705,424

Examiner

Hieu Phan

Applicant(s)/Patent under  
Reexamination

LITVACK ET AL.

Art Unit

3738

## SEARCHED

Class	Subclass	Date	Examiner
update	search	10/13/2005	☞

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR